# **Product Specification** 108-5134

## AMP-MODU "J" Series Connector (Lever Lock Type)

#### 1. Scope :

This specification covers product performance requirements and test methods of AMP-MODU "J" Series Connector (lever lock type) of the following part numbers.

Part Numbers	Part Name	Descriptions
172756 <b>-</b> X		AWG #22-26,
170433-X	Receptacle Contact	AWG #26-28,
<u>170435-x</u> <u>170437-x</u> 171275-1, -3		" #20-24, " " #20-24, " #20-24,
172145-X	Receptacle Housing	with Locking Ears
172091-X 172092-X	AMP-LATCH "J" Series, Post Header Vertical Type	w/o External Locking Lever w/ External Locking Lever
172093-X 172094-X	AMP-LATCH "J" Series, Post Header Horizontal Type	w/o External Locking Lever w/ External Locking Lever
173210-X	Receptacle Housing	Panel-Mounting Type

2. Applicable Documents:

2.1 The following standard and specifications form part of this specification to the extent specified herein.

2.1.1 Military Standard/Specifications and Federal Specifications:

Test Methods for Electronic and Electrial Component Parts MIL-STD-202 MIL-B-45204 Electrodeposited Gold-Plating

2.1.2 Federal Specifications:

QQ-C-533	Copper-Beryllium	Alloy Strip
QQ-N-290	Electrodeposited	Nickel Plating

- QQ-B-750 Phosphor Bronze Strip · · · · ·
- 2.1.3 Japanese Standard:

JIS-H-3521 Brass Wires

### For the purpose of this specification, the following terms shall apply. 3.

3.1 Receptacle Contact:

> Electrically conductive metallic component, having stamped form as a female contact with "U" barrels to crimp wire conductor and insulation. Frictional contact area is formed in a square box configuration, and a pair of cantilever springs to make electrical contact with pin contact when mated. The receptacle contact is also featured to have a locking lance to retain with when installed in housing cavity. Improved back-up mechanism is provided on the lance of 172656-X.

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#### 3.2 Receptacle Housing:

An electrically insulating multi-pole connector housing that is plastic molded by using the material specified in Para. 4.2, to encapsulate receptacle contacts in the cavities with the center line spacing disposition in 2.54mm laterally and longitudinally.

#### 3.3 Post Header Assembly:

AMP-LATCH "J" Series post headers having 0.64mm dia. posts implanted with the center line spacing of 2.54mm are used for this application. The root portion of pin contacts is inserted in the printed circuit . board hole and soldered, and tip end of the pin contact engages with receptacle contact to complete circuitry. The housings of both vertical and horizontal types with the locking levers to lock the mated housing, are available.

3.4 Connector Assembly:

> Connector Assembly is an assembly of receptacle contact-loaded housing and pin contact-loaded post header adequately engaged to complete circuitry.

4. Material and Finish:

4.1 Receptacle Contact:

Beryllium-Copper Alloy conforming to QQ-C-533 4.1.1 Material: Phosphor Bronze conforming to QQ-B-750

4.1.2 Finish: Gold strip plating having thickness of 0.4µm or 0.76µm min. or gold selective gold plating having thickness of 0.4µm average, conforming to MIL-G-45204, over nickel underplate having thickness of 0.4 - 1.0µm or 1.3 - 2.5µm conforming. to QQ-N-290: Tin-plating 0.8µm minimum

4.2. Receptacle Housing and Post Housing:

4.2.1 Glass-filled polybuthylene terephthalate resin, conforming Material: UL Fire Retardant Grade of UL 94V-0.

4.3 Post Contact:

4.3.1 Brass Wire #4, conforming to JIS H 3521 Material:

Finish: (a) Gold-plating 0.2µm, 0.4µm and 0.8µm min. thick over 1.3µm min. 4:3:2 . - . . . . . nickel underplate, 

(b) Bright tin plating 0.8µm min. over 0.8µm min. bright nickel underplate

5. Appearance and Color:

#### 5.1 Appearance:

Product must appear normal without showing evidence of defects such as damages, breakage, deformation, blister dirt and burrs that are detrimental to connector functions and cosmetic appearance.

5.2 Color:

Housing color must be black as specified.

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34	6.	Product Design Feature, Construct	ion and Dimensions:
1, 5			ion and dimensions shall be conforming t drawing(s). Major features of the
помвел	(1) (2)	Number of Connector Positions: Center Line Spacing:	10, 16, 20, 26, 34, 40 and 50 Positions 2.54mm x 2.54mm Dual Line
или	(3)	Type of Post Header Assemblies:	Vertical and Horizontal
	(4)	Mounted Method of Post Header:	Screw on printed circuit board and soldered
mer ise	(5)	Mounting Method of Receptacle Housing (Panel-Mounting Type):	Screw on the panel.
Customer Release	(6)	Applicable Wire Size:	AWG #20 - #28, Insulation diameter: 0.89 - 1.77mm
1	7.	Performance:	
1 V I ON	7.1	Rated Performance:	
FICAT		Temperature Rating:	105°C55°C
AMP SECURITY CLASSIFICATION		Current Rating:	3.5A for AWG#20-24, 2A for AWG#26-28 Wire
<u> </u>	7.2	Electrical Performance:	
	Test		

Test Items (Paragraph No.)	Specified Requirement	Summary of Test Method
Termination Resistance (Low Level) (Para. 7.2.1)	18mΩ Maximum (Gold plated contacts) 20mΩ Maximum (Tin plated products)	Termination resistance of contact is tested in accordance with Test Method 307 of MIL-STD-202 by ap- plying closed circuit current of 50mA max. at open circuit voltage of 50mV flowing through the cir- cuit formed as specified in Fig. 2. From the measured reading, the resistance of 75mm-long wire must be duducted. Calculate termination resistance.
Insulation Resistance: (Para. 7.2.2)	5,000MΩ min.	Insulation resistance of mated pair of connector assemblies must be measured in accordance with Test Condition "B", Test Method " 302 of MIL-STD-202 by applying" test potential between the adja- cent contacts and between the op- posing side contacts. Measure- ment shall be done on randomly selected 4 pairs of contacts.
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### 7.2 Electrical Performance:

5	Test Items (Paragraph No.)	Specified Requirements	Summary of Test Method
mer 100-01 100-04	Dielectric Strength (Para. 7.2.3)	Connector assembly shall withstand test potential for 1 minute without show- ing abnormalities such as insulation breakdown and flashover on connector sur- faces.	Dielectric strength of mated pair of connector assemblies shall be tested in accordance with Test Method 301 of MIL-STD-202 by ap- plying test potential between the adjacent and opposing contact in- creasing at a rate of 500V/sec.AC until the specified limit at 500V is reached. Hold at 500V for 1 minute and inspect for evidence of abnormalities.
		105°C max.	Before energizing test current, 1.5mm dia. hole is made through the wall of housing cavity at the portion where wire barrel is po- sitioned as shown in Fig. 3. Then apply test current of the value specified in Table 1. Measure-th temperature rising of contact by probing on five contacts in the interior disposition after the temperature rising of connector becomes stabilized. The measure- value must not exceed the maximum limit specified in Table 1 in Par 7.1.

### 7.3 Physical Performance:

Test Items (Paragraph No.)	Specified Requirements	Summary of Test Method
Connector Insertion and Extraction Force (Para. 7.3.1)	Insertion Force:370 g (max.) Extraction Force: 30 g (min.) (Gold plated products)	A mating pair of connector assem- blies shall be fastened on the tensile testing machine in the manner they are to mate and unmat as the head is operated. Measure
	Insertion Force: 450 g (max.) Extraction Force: 30 g (min.) (Tin plated products)	the force required to engage and separate without locking legs set in effect. Measured value must b divided by the number of contact positions to obtain averaged in- sertion/extraction force of one contact position of connector.

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ation a. 7.3.3)	connec show r damage Termina <u>Resista</u> Insert Extrac Force: During electr greate shall no abr breaka	test co ctor ass to abnor es. tion nce(min lon/ tion tion tical di er than occur, hormalit age, dan	Plati Gold Plata Gold 18mΩ Para. shall t tile tes tiscontin 1 μseco and sha ties suc mage and the conn	hall s and <u>Tin</u> <u>2OmΩ</u> '.3.1 be met. ting, uity nd ll show h as	shall be tested in Test Method 201A o:	Number of Cycles ts 100 s 20 ector assemblic accordance wit f MIL-STD-202,t
	Resista Insert Extrac Force: During electr greate shall no abr breaka	nce(min ion/ tion ical di er than occur, ormalit age, dan	Gold 18mΩ Para. shall t ile tes iscontin l μseco and sha ties suc nage and	<u>Tin</u> 2OmΩ <sup>•</sup> ·.3.1 be met. ting, uity nd ll show h as	Gold Plated Product Tin Plated Product Mated pair of conne shall be tested in Test Method 201A o	Cycles ts 100 s 20 ector assemblie accordance wit f MIL-STD-202,t
	Resista Insert Extrac Force: During electr greate shall no abr breaka	nce(min ion/ tion ical di er than occur, ormalit age, dan	Para. ; shall t ile tes iscontin l µseco and sha ties suc nage and	'.3.1 ting, uity nd ll show h as	Tin Plated Product Mated pair of conne shall be tested in Test Method 201A o	s 20 ector assemblie accordance wit f MIL-STD-202,t
	Extrac Force: During electr greate shall no abr breaka	vibratical di ical di er than occur, normaliticage, dan	tile tes scontin l µseco and sha ties suc nage and	ting, uity nd ll show h as	Mated pair of conne shall be tested in Test Method 201A o:	ector assemblic accordance wit f MIL-STD-202,t
	electr greate shall no abr breaka	ical di er than occur, normalit nge, dan	iscontin lµseco and sha ties suc mage and	uity nd ll show h <b>as</b>	shall be tested in Test Method 201A o	accordance wit f MIL-STD-202,t
ntion Force of ptacle Contact:			ontact s i from t	ector. hall be	chine where sample connector is supported without allowing term nated wires to touch the plate. During the test, all the contac shall be series wired and monit ed for electrical discontinuity greater than 1 µsecond with the use of test current of 0.1A flo ing through the circuit. Fasten contact-loaded connector tensile testing machine and app	
						load to the end operating the h the speed at nute. The for- ge the contact
Tensile Strength: a. 7.3.5)	<u>Wire</u> mm <sup>2</sup>	Size (AWG)			Wire crimped contact fastened on the ter	
	0.5	(#20)	7.9	min.	chine and an axial	pull-off load
	0.3	(#22)	4.9	<u>†1</u>		
	0.2	(#24)	3.1	H	to travel with the	speed at a ray
	0.14	(#26)	1.8	11	strength is determ	ined when the
	0.085	(#28)	1.2		wire is broken or from the wire crim	
	o Tensile Strength:	tact p o Tensile Strength: a. 7.3.5) 0.5 0.3 0.2 0.14	tact position Tensile Strength: a. 7.3.5) Wire Size mm <sup>2</sup> (AWG) 0.5 (#20) 0.3 (#22) 0.2 (#24) 0.14 (#26)	tact position within Tensile Strength: a. 7.3.5) Wire Size Crimp T mm <sup>2</sup> (AWG) 0.5 (#20) 0.3 (#22) 0.2 (#24) 0.14 (#26) 1.8	tact position within 1.5kg. • Tensile Strength: • 7.3.5) • Wire Size Crimp Tensile mm <sup>-</sup> (AWG) Strength (kg) • 0.5 (#20) 7.9 min. • 0.3 (#22) 4.9 " • 0.2 (#24) 3.1 " • 0.14 (#26) 1.8 "	tact position within 1.5kg.an axial pull off of crimped wire by head to travel with rate of 100mm a minicequired to dislod shall be measuredo Tensile Strength:Wire Size mm² (AWG)Crimp Tensile Strength (kg)Wire crimped conta fastened on the ten chine and an axial shall be applied to crimped wire by op- to travel with the of 100mm a minute. strength is determ 0.085 (#28)1.2

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Test Items (Paragraph No.)	Specified Requirements	Summary of Test Methods
Soldering Heat Resistibility: (Para. 7.3.6)	After test conditioning, sample shall show no abnor- malities such as rattling of post, cracks and deform- ation of housing.	Condition "B"(260°C, 10 seconds)
		time of 10 <sup>±</sup> 1 seconds. Soldering tub shall be controlled at 260 <sup>±</sup> 5
7.4 Environmental	Performance:	
Test Items (Paragraph No.)	Specified Requirements	Summary of Test Methods
Thermal Shock: (Para. 7.4.1)	After conditioning, connec- tor shall show no evidence of cracks, warpage and bench however changes of color and surface tactility are not causing for rejection. Insertion/extraction func- tion of connector shall be kept feasible after testing	shall be tested in accordance wi Test Condition "A", Test Method 107 of MIL-STD-202 excepting upp temperature limit to be +105°C After specified thermal test cyc ing, appearance inspection and functional test shall be perform
Humidity:(Steady State) (Para. 7.4.2	After test conditioning,Insulation Resistance100MQ min.Dielectric StrengthPara. 7.2.3Strengthshall be met.Termination Resistance (Low Level)Plating Type18mQ (max.)20mQ (max.)	Mated pair of connector assembli shall be tested in accordance wi Test Condition "B", Test Method 103 of MIL-STD-202. After compl tion of test duration, sample shall be reconditioned in the re temperature for 24 hours, before undergoing subsequent measuremen
Salt Spray: (Para. 7.4.3)	After test conditioning,evidence of abnormalitiessuch as remarkable corrosion and physical defectsshall be present.TerminationResistance(Low Level)Gold18m220m2(max.)	Mated pair of connector assemble shall be tested in accordance we Test Condition B, Test Method 1 of MIL-STD-202. After completin of test duration, sample connect shall be linsed in tap water and dried in room temperature without aid of powered ventilation.
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8. Test Conditions:

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8.1 Environmental Conditions:

Unless otherwise specified, all the tests shall be performed under any combination of the following conditions:

Temperature:	15	-	35°C
Relative Humidity:	45	-	75%
Atmosphric Pressure:	650	-	800 mmHg

8.2 Test Specimens:

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8.2.1 Test specimens to be used for testing under this product specification shall be prepared by using products selected from the current production at random that are conforming to the applicable product drawing(s).

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9. Test Sequence:

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-513	Test Items	Para- graph No.			Assemblies			P <sub>ost</sub> Header	Crimped Contact
108			1	2	3	4	5	6	7
SECURITY CUSTOMET ALMADER	Appearance (Initial)	5.1							
	Termination Resistance (Low Level) (Initial)	7.2.1	$\boxed{3}$	2		2	2		
	Insulation Resistance (Initial)	7.2.2	<b>i</b>						
	Dielectric Strength (Initial)	7.2.3		4					
	Temperature Rising	7.2.4			2				
	Connector Insertion and Extraction Force (Initial)	7.3.1	2						
	Durability, (Repeated Insertion/Extraction)	7.3.2	4						
	Vibration	7.3.3	6		1		$\bigcirc$		
	Receptacle Contact Retention Force	7.3.4			(4)			-	
	Crimp Tensile Strength	7-3-5		· ·					2
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	Thermal Shock	7.4.1		(5)					
	Humidity (Steady State)	7.4.2							
	Salt Spray	7-4-3	9			$\Box$			
	Termination Resistance (Low Level) (Final)	7.2.1	8.10	8		4	_4		
	Insulation Resistance (Final)	7.2.2		) ତା		e e			
	Dielectric Strength (Final)	7.2.3		10					
	Connector Insertion/ Extraction Force (Final)	7.3.1	5						
	Appearance (Final)	5.1	(7,1)	6	3	5	5	3	
	Number of Specimens		5 Sets	5 Sets	2 Sets	3 Sets	3 Sets	5 Sets	10 Pcs

(Note:)

- 1. Tests are performed in accordance with the sequence shown in the columns above.
- 2. Sample Group 3 shall consist of two sets of specimens each prepared for accepting the wires of AWG #20-24 and #26-28 respectively.
- 3. Sample Group 5 shall consist of crimped contacts prepared for each wire size used for termination of specimens.
- 4. Gold-plated contacts shall be omitted from the Sample Groups 4 and 5. Tin-plated contacts shall be included in the Sample Groups 1 through 7. However, the test items No. 6, 7, 8 and 9 in the Sample Group 1 shall be omitted.

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